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Introduction

We have the great honor of organizing the 3rd International Symposium on Photoelectronic Detection and Imaging (ISPDI) in Beijing, following the 1st and 2nd ISPDI held successfully in Beijing in 1993 and 2007. It is truly a great pleasure for us to greet more than 1,000 participants from many different countries attending ISPDI 2009! I firmly believe that the symposium will become an important international event in the field of photoelectronic detection and imaging technology.

ISPDI 2009 is sponsored by the Photoelectronic Technology Professional Committee and the Chinese Society of Astronautics, and is organized by Tianjin Jinhang Institute of Technical Physics. There are also 25 cooperating organizations that support the meeting. About 700 papers were accepted for presentation and 1,300 abstracts were submitted from more than 10 countries, including the United States, United Kingdom, Germany, France, Norway, Sweden, Demark, Canada, Japan, Republic of Korea, Russian Federation, China, and so on. We have over 90 internationally renowned scientists and experts who were invited to speak.

The purpose of ISPDI 2009 is to provide a forum for the participants to report and review the ideas, up-to-date comprehensive progress, and developments, and to discuss novel approaches to application areas in the field of photoelectronic detection and imaging. It is sincerely hoped that the research and development in photoelectronic detection and imaging will flourish, and that international cooperation of our the common interests will be enhanced.

I would like to heartily thank our sponsors and cooperative organizations for all they have done for the meeting. Thanks also to all the authors for their contributions to these proceedings, to all of the participants and friends for their interest and efforts in helping to make the symposium possible; to the organizing committee and the program committee for their effective work and valuable advice, especially the ISPDI 2009 Secretariat, and to the SPIE staff for their tireless effort and outstanding service in preparing and publishing the conference proceedings.

Again, we extend our warmest greetings to you and hope you have a rewarding and exciting stay during ISPDI 2009!

Liwei Zhou

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